

IAF12 Rec'd PCT/PTO 03 FEB 2006

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of)	Examiner: Unknown
Michael C. VAN BEEK, et al.)	Art Unit: Unknown
)	
Serial No.: not assigned)	
)	
Filed: herewith)	
)	
Title: System for Dark-Field Imaging of)	
Target Areas Below an Object)	
Surface)	
)	
Attorney Docket No.: PHNL030944US)	Cleveland, Ohio 44143
		February 3, 2006

Information Disclosure Statement under 37 CFR 1.97(b)(3)

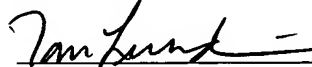
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Further to the filing of the National Stage Entry of PCT patent application, serial number PCT/IB2004/051327, Applicants submit an Information Disclosure Statement under 37 CFR 1.97(b)(3). Along with the foreign references, applicants also enclose a form PTO/ISB/08A listing all of the references for the Examiner's convenience.

Applicants believe that no charge is due for the submission of this Information Disclosure Statement. However, please charge any necessary fees in connection with this submission to our Deposit Account No. 14-1270.

Respectfully submitted,



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USPTO form PTO/SB/08A

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Subst. Form PTO-1449 APPLICANT'S(S') INFORMATION DISCLOSURE STATEMENT		Atty. Dkt No.: PHNL030944US Applicant(s): Michael C. VAN BEEK, et al. Filing Date: herewith		Serial No.: Unknown 10/567284 Group: unknown	
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U.S. PATENT DOCUMENTS							
Initial *		Document No.	Date	Name	Class	Subcl	Filing Date
	AA	5,813,987	09-29-1998	Modell, et al.	600	473	12-24-1996
	AB	5,983,120	11-09-1999	Groner, et al.	600	310	06-05-1997
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		Document No.	Date	Name			Translation ?
	AF	WO 00/27276 A1	05-18-2000	Cytometrics, Inc.			
	AG	WO 00/57146 A1	09-28-2000	Cytometrics, Inc.			
	AH	WO 01/22741 A2	03-29-2001	Nadeau, et al.			
	AI	WO 02/057759 A1	07-25-2002	KPENV			
	AJ	EP 0 468 817 A2	01-29-1992	Booker, et al.			
	AK	EP 0 714 628 A1	06-05-1996	TOA Medical			

OTHER ART	
	AL http://www.olympusmicro.com/primer/techniques/darkfieldindex.html Darkfield Microscopy techniques
	AM
	AN

Examiner:	Date Considered:
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if in conformance and not considered. Include copy of this form with next communication to applicant.